

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10676819	WEDEL ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Chen, Qing	2191

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
717	100-103,110-113	6/17/2010	/QC/
714	19	6/17/2010	/QC/
715	700,771	6/17/2010	/QC/
345	666	6/17/2010	/QC/

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Updated EAST Search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) -- See Search History Printout	6/17/2010	/QC/
717/100-103,110-113; 714/19; 715/700,771; 345/666 (limited class search using keywords)	6/17/2010	/QC/
Updated EAST Inventor Name Search and Assignee Search (US-PGPUB; USPAT) -- See Search History Printout	6/17/2010	/QC/
Updated PALM Inventor Name Search	6/17/2010	/QC/
Consulted SPE Wei Zhen (AU 2191)	6/17/2010	/QC/

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
717	100-103,110-113	6/17/2010	/QC/
714	19	6/17/2010	/QC/
715	700,771	6/17/2010	/QC/
345	666	6/17/2010	/QC/

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